

Radioactive Cleanliness Control for the JUNO Experiment

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Purpose: keep a JUNO detector CLEAN (ultra-low radioactivity), not only control bulk radioactive background from material and environment, but also need control surface cleanliness due to dust fallout during manufacture, installation, commissioning and etc. In order to reach 10⁻¹⁵ g/g U/Th background for neutrino mass hierarchy determination, we will investigate both effective cleaning methods and evaluation techniques. We will do more effort to achieve 10^{-17} g/g U/Th background to explore more physics.

Background consideration

Total radioactive budget for the JUNO detector:

9.6 Hz (in fiducial volume (FV) and >0.7 MeV)

Radioactive budget for the surface cleanliness contribution:

Dust contribution inside CD: < 0.32 Hz (in FV and >0.7 MeV)

Dust contribution outside CD: < 0.25Hz (in FV and >0.7 MeV)

Dust fallout models

General Model:

Class 10000, dust fall rate: 0.09 mg/m²/day $M_{dust}=D_{clean_level} \times V_{accumulation_rate} \times Area \times Time$

M_{dust}: Mass of accumulated dust

D_{clean level}: density of dust under a clean level

V_{accumulation rate}: wind speed assume all the dust accumulated

Daya Bay Model:

Class 10000, dust fall rate: 0.14 mg/m²/day

During one Daya Bay acrylic vessel (AV) production and assembly, dust could fallout on the AV surface. γ from 232 Th and 238 U decay chains can be seen. The time of production and assembly for each AV is different, ²³⁸U/²³²Th contaminations could be observed. Then fallout rate can be estimated.

Measured dust radioactivity:

U-238: 9.7ppm, Th-232: 26.6ppm, K-40: 5.1ppm

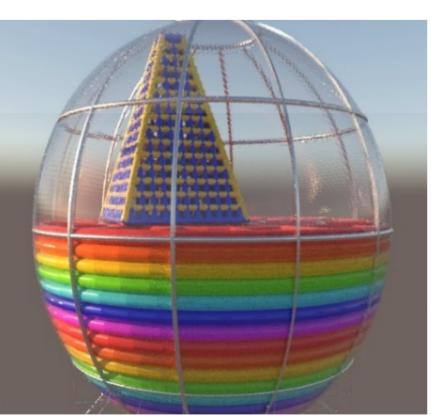
Cleaning methods

Acrylic clean strategy

Acrylic sphere cleaning



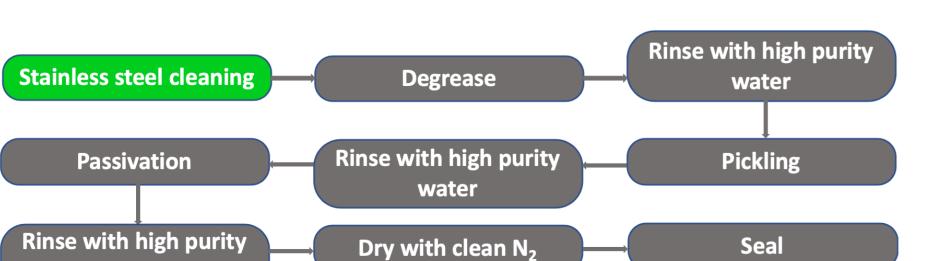


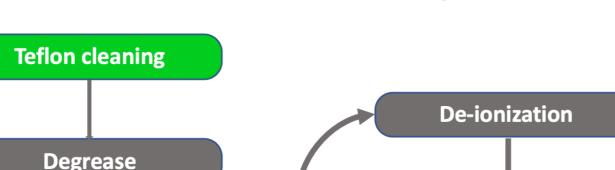


Water spray

Wipe with air cushions

Stainless steel cleaning





Teflon cleaning

Degrease Seal and protection Rinse with high purity

Evaluation methods

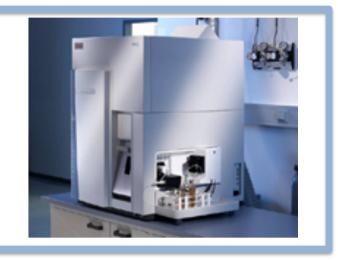
1. Conductivity monitoring

Resistivities of water before and after cleaning surface will be measured, the difference should be less than 4-6 M Ω ·cm (circulation or rinse method). Original cleaning water quality should be 18.2 M Ω ·cm.



2. Light absorption spectra comparison

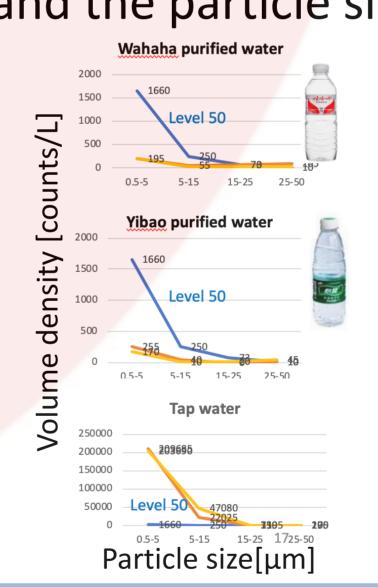
Compare the light absorption spectra with rinsed water before and after cleaning surface. The spectra are in a good agreement.



3. Suspension particulate counting

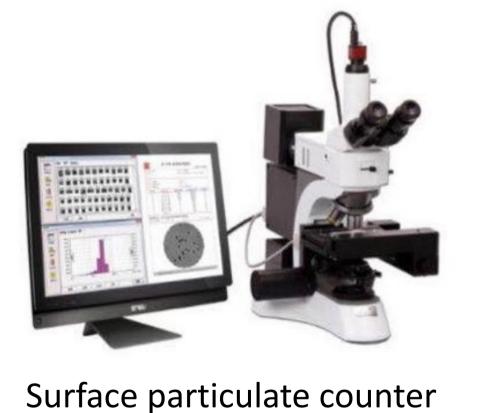
- A. Verification with rinsing water measurement
 - Detector: Silicon Photodetector, Photodiode
 - Measuring range: 0.5μm to 400μm
 - Light obscuration(extinction) and angular scattering combination advanced technologies make the measuring wider and accurate.
 - Repeatability deviation: < 5%
 - Particle size, cleanliness level and the particle size distribution can be obtained.

[um]	[coun	ts/0.1m ²]	[cour	nts/L]	
5		179	16	60	
15		27.0	25	50	
25	7	7.88	7	3	
50		1.01	1	0	
JUNO Level 50					
	Volume density [counts/L]				
Particle Size μm	5	5-15	15-25	25-50	
Particle Size μm WaHaHa bottle water 1	5 195	5-15 55	15-25 70	25-50 105	
WaHaHa bottle water 1	195	55	70	105	
WaHaHa bottle water 1 WaHaHa bottle water 2	195 200	55 35	70 25	105 20	
WaHaHa bottle water 1 WaHaHa bottle water 2 Yibao bottle water 1	195 200 255	55 35 40	70 25 0	105 20 10	
WaHaHa bottle water 1 WaHaHa bottle water 2 Yibao bottle water 1 Yibao bottle water 2	195 200 255 170	55 35 40 10	70 25 0 20	105 20 10 45	



- B. Particulate counting with monitoring witness plates
- High speed camera + microscope + algorithm
- Measuring range: 1μm to 10000μm
- Repeatability deviation: < 1%
- Sampling speed: 10000 counts/min
- Enlargement factor: 30-1000
- Duration: 10 mins



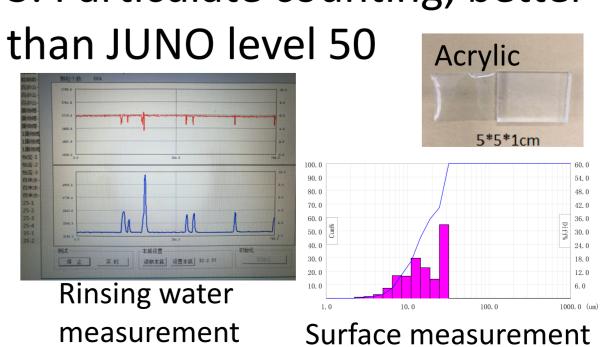


4. ICP-MS measurement: sensitivity: 10⁻¹³ g/g for ²³⁸U and ²³²Th

Cleanliness requirement						
	Purificatio n and filling system	Acrylic sphere (inner surface)	Acrylic sphere (outer surface)	Calibration system		
Area	772 m²	4000 m ²	4000 m ²	< 2 m ² (cable & source capsule)	< 4 m ² (cable & positioning system)	
Surface dust requirement for cleaning	< 0.1 mg/m ²	< 1.7 mg/m ²	< 3.1 mg/m ²	< 0.1 mg/m ²	< 1.7 mg/m ²	
Allow exposure in class 10000 space after cleaning	< 0.15 days	12 days	6 months	< 0.15 days	12 days	
Total surface background budget (Singles in	< 0.22 Hz	< 0.1 Hz	< 0.25 Hz	< 0.4 mHz	< 0.4 mHz	

Preliminary results of acrylic panel test

- 1. Conductivity monitoring Measured resistivity of rinsing water before and after cleaning is less than 4M′Ω·cm
- 3. Particulate counting, better than JUNO level 50



2. Light absorption spectra

Ultrapure water after acrylic clean 0.070 0.050 0.030

4. ICP-MS measurement, the rinsing water before and after acrylic cleaning

Conc. [ppt]	Before	After
²³⁸ U	<0.17 @90% C.L.	0.13 <u>±</u> 0.01
²³² Th	<0.01 (MDA)	<0.18 @90% C.L.